

December 1996

Fast CMOS Octal Bus Transceiver (Three-State)

Features

- Advanced 0.8 micron CMOS Technology
- CD74FCT623T is Pin Compatible with Bipolar FAST™ Series at a Higher Speed and Lower Power Consumption
- TTL Input and Output Levels
- Extremely Low Static Power
- Hysteresis on All Inputs

Description

The CD74FCT623T is an 8-bit wide non-inverting octal transceiver designed with three-state bus-driving outputs in both the send and receive directions. Designed for asynchronous two-way operation between data buses, the control function allows for maximum flexibility in timing.

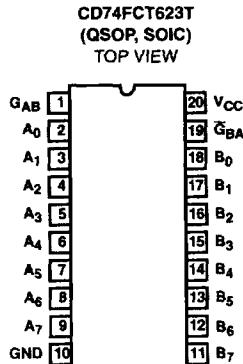
Ordering Information

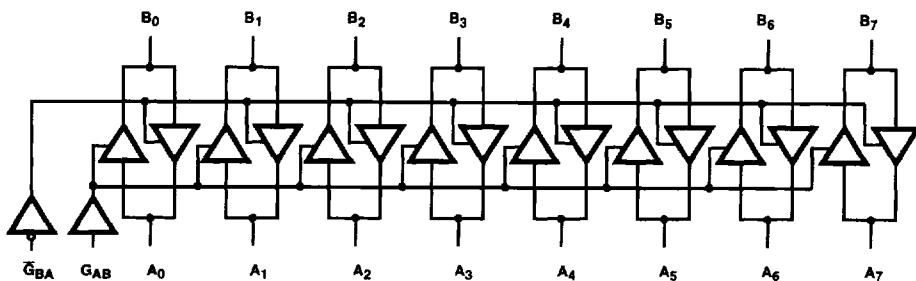
PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74FCT623TM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT623ATM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT623CTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT623DTM	-40 to 85	20 Ld SOIC	M20.3-P
CD74FCT623TQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT623ATQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT623CTQM	-40 to 85	20 Ld QSOP	M20.15-P
CD74FCT623DTQM	-40 to 85	20 Ld QSOP	M20.15-P

NOTE: QSOP is commonly known as SSOP.

When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

Pinout



Functional Block Diagram

TRUTH TABLE (NOTE 1)

INPUTS		OUTPUTS
\bar{G}_{BA}	G_{AB}	
L	L	B Data to A Bus
H	H	A Data to B Bus
H	L	Z
L	H	B Data to A Bus A Data to B Bus

NOTE:

- 1. H = High Voltage Level
- L = Low Voltage Level
- Z = High Impedance (OFF) State

Pin Descriptions

PIN NAME	DESCRIPTION
\bar{G}_{BA}, G_{AB}	Enable Outputs
A_0-A_7	A Bus Inputs or Three-State Outputs
B_0-B_7	B Bus Inputs or Three-State Outputs
GND	Ground
V _{CC}	Power

4
OCTAL 5V FCT
5V FCT 25Ω

Absolute Maximum Ratings

DC Input Voltage	-0.5V to 7.0V
DC Output Current	120mA

Operating Conditions

Operating Temperature Range	-40°C to 85°C
Supply Voltage to Ground Potential Inputs and V _{CC} Only.....	-0.5V to 7.0V
Supply Voltage to Ground Potential Outputs and D/O Only.....	-0.5V to 7.0V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

2. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Thermal Information

Thermal Resistance (Typical, Note 2)	θ _{JA} (°C/W)
SOIC Package	87
QSOP Package	110
Maximum Junction Temperature	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C
(Lead Tips Only)	

Electrical Specifications

PARAMETER	SYMBOL	(NOTE 3) TEST CONDITIONS		MIN	(NOTE 4) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, T _A = -40°C to 85°C, V _{CC} = 5.0V ±5%							
Output HIGH Voltage	V _{OH}	V _{CC} = Min, V _{IN} = V _{IH} or V _{IL}	I _{OH} = -15.0mA	2.4	3.0	-	V
Output LOW Voltage	V _{OL}	V _{CC} = Min, V _{IN} = V _{IH} or V _{IL}	I _{OL} = 64mA	-	0.3	0.50	V
Input HIGH Voltage	V _{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage	V _{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Input HIGH Current	I _{IH}	V _{CC} = Max	V _{IN} = V _{CC}	-	-	1	μA
Input LOW Current	I _{IL}	V _{CC} = Max	V _{IN} = GND	-	-	-1	μA
High Impedance Output Current	I _{OZH}	V _{CC} = Max	V _{OUT} = 2.7V	-	-	1	μA
	I _{OZL}		V _{OUT} = 0.5V	-	-	-1	μA
Clamp Diode Voltage	V _{IK}	V _{CC} = Min, I _{IN} = -18mA		-	-0.7	-1.2	V
Short Circuit Current	I _{OS}	V _{CC} = Max (Note 5), V _{OUT} = GND		-60	-120	-	mA
Power Down Disable	I _{OFF}	V _{CC} = GND, V _{OUT} = 4.5V		-	-	100	μA
Input Hysteresis	V _H			-	200	-	mV
CAPACITANCE T _A = 25°C, f = 1MHz							
Input Capacitance (Note 6)	C _{IN}	V _{IN} = 0V		-	6	10	pF
Output Capacitance (Note 6)	C _{OUT}	V _{OUT} = 0V		-	8	12	pF
POWER SUPPLY SPECIFICATIONS							
Quiescent Power Supply Current	I _{CC}	V _{CC} = Max	V _{IN} = GND or V _{CC}	-	0.1	10	μA
Supply Current per Input at TTL HIGH	ΔI _{CC}	V _{CC} = Max	V _{IN} = 3.4V (Note 7)	-	0.5	2.5	mA
Supply Current per Input per MHz (Note 8)	I _{CCD}	V _{CC} = Max, Outputs Open G _{BA} = G _{AB} = GND One Input Toggling 50% Duty Cycle	V _{IN} = V _{CC} V _{IN} = GND	-	0.15	0.25	mA/ MHz

Electrical Specifications (Continued)

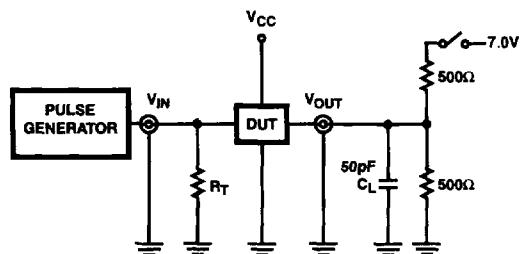
PARAMETER	SYMBOL	(NOTE 3) TEST CONDITIONS				MIN	(NOTE 4) TYP	MAX	UNITS
		V _{CC} = Max, Outputs Open f _{CP} = 10MHz, 50% Duty Cycle G _{BA} = G _{AB} = GND, 50% Duty Cycle One Bit Toggling at f _I = 5MHz	V _{IN} = V _{CC} V _{IN} = GND	-	1.7		4.0 (Note 9)		
Total Power Supply Current (Note 10)	I _C	V _{CC} = Max, Outputs Open f _{CP} = 10MHz, 50% Duty Cycle G _{BA} = G _{AB} = GND, 50% Duty Cycle, Eight Bits Toggling at f _I = 2.5MHz, 50% Duty Cycle	V _{IN} = 3.4V V _{IN} = GND	-	2.0	5.0 (Note 9)	mA	mA	mA
			V _{IN} = V _{CC} V _{IN} = GND	-	3.2	6.5 (Note 9)	mA		
Total Power Supply Current (Note 10)	I _C	V _{CC} = Max, Outputs Open f _{CP} = 10MHz, 50% Duty Cycle G _{BA} = G _{AB} = GND, 50% Duty Cycle, Eight Bits Toggling at f _I = 2.5MHz, 50% Duty Cycle	V _{IN} = 3.4V V _{IN} = GND	-	5.2	14.5 (Note 9)	mA	mA	mA

Switching Specifications Over Operating Range

PARAMETER	SYMBOL	(NOTE 11) TEST CONDITIONS	T		AT		CT		DT		UNITS
			(NOTE 12) MIN	MAX							
CD74FCT138T											
Propagation Delay A _N to B _N	t _{PLH} , t _{PHL}	C _L = 50pF R _L = 500Ω	1.5	7.5	1.5	5.5	1.5	4.8	1.5	3.8	ns
Propagation Delay B _N to A _N	t _{PZH} , t _{PLH}		1.5	7.5	1.5	5.5	1.5	4.8	1.5	3.8	ns
Output Enable Time G _{BA} to A _N	t _{PZH} , t _{PZL}		1.5	9.0	1.5	7.0	1.5	6.1	1.5	5.0	ns
Output Disable Time G _{BA} to A _N (Note 13)	t _{PHZ} , t _{PLZ}		1.5	8.0	1.5	6.5	1.5	5.6	1.5	4.3	ns
Output Enable Time G _{AB} to B _N	t _{PZH} , t _{PZL}		1.5	9.0	1.5	7.0	1.5	6.1	1.5	5.0	ns
Output Disable Time G _{AB} to B _N (Note 13)	t _{PHZ} , t _{PLZ}		1.5	8.0	1.5	6.5	1.5	5.6	1.5	4.3	ns

NOTES:

3. For conditions shown as Max or Min, use appropriate value specified under Electrical Specifications for the applicable device type.
4. Typical values are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
5. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
6. This parameter is determined by device characterization but is not production tested.
7. Per TTL driven input (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.
8. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
9. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
10. I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}
I_C = I_{CC} + ΔI_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_I N_I)
I_{CC} = Quiescent Current
ΔI_{CC} = Power Supply Current for a TTL High Input (Vin = 3.4V)
D_H = Duty Cycle for TTL Inputs High
N_T = Number of TTL Inputs at D_H
I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HHL or LHL)
f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)
f_I = Input Frequency
N_I = Number of Inputs at f_I
All currents are in millamps and all frequencies are in megahertz.
11. See test circuit and wave forms.
12. Minimum limits are guaranteed but not tested on Propagation Delays.
13. This parameter is guaranteed but not production tested.

Test Circuits and Waveforms**SWITCH POSITION**

TEST	SWITCH
t_{PLZ}, t_{PZL}	Closed
$t_{PHZ}, t_{PZH}, t_{PLH}, t_{PHL}$	Open

DEFINITIONS:

C_L = Load capacitance, includes jig and probe capacitance.
 R_T = Termination resistance, should be equal to Z_{OUT} of the Pulse Generator.

NOTE:

14. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $Z_{OUT} \leq 50\Omega$;
 $t_i, t_f \leq 2.5\text{ns}$.

FIGURE 1. TEST CIRCUIT

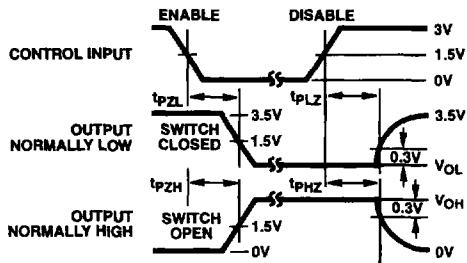


FIGURE 2. ENABLE AND DISABLE TIMING

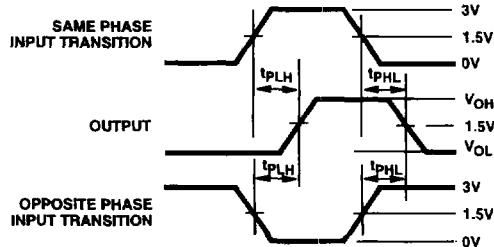


FIGURE 3. PROPAGATION DELAY